

QA of pre-production Mu2e SiPMs

MUSE General Meeting

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Mu2e SiPM technical specs (docdb-7052)

- R1) a relative spread in V_{op} (operational voltage) between the sensor cells $< 0.5\%$.
- R2) a relative spread in the dark current at V_{op} between the sensor cells $< 15\%$.
- R3) a gain (measured in a gate of 150 ns) at $V_{op} > 10^6$ for each cell.
- R4) a PDE at $V_{op} > 20\%$ for 315 nm, evaluated using a reference-device.
- R7) a recovery time $\tau < 100$ ns on a load greater than 15 Ω .

Sensors that don't meet the requirements are discarded.

What we measured

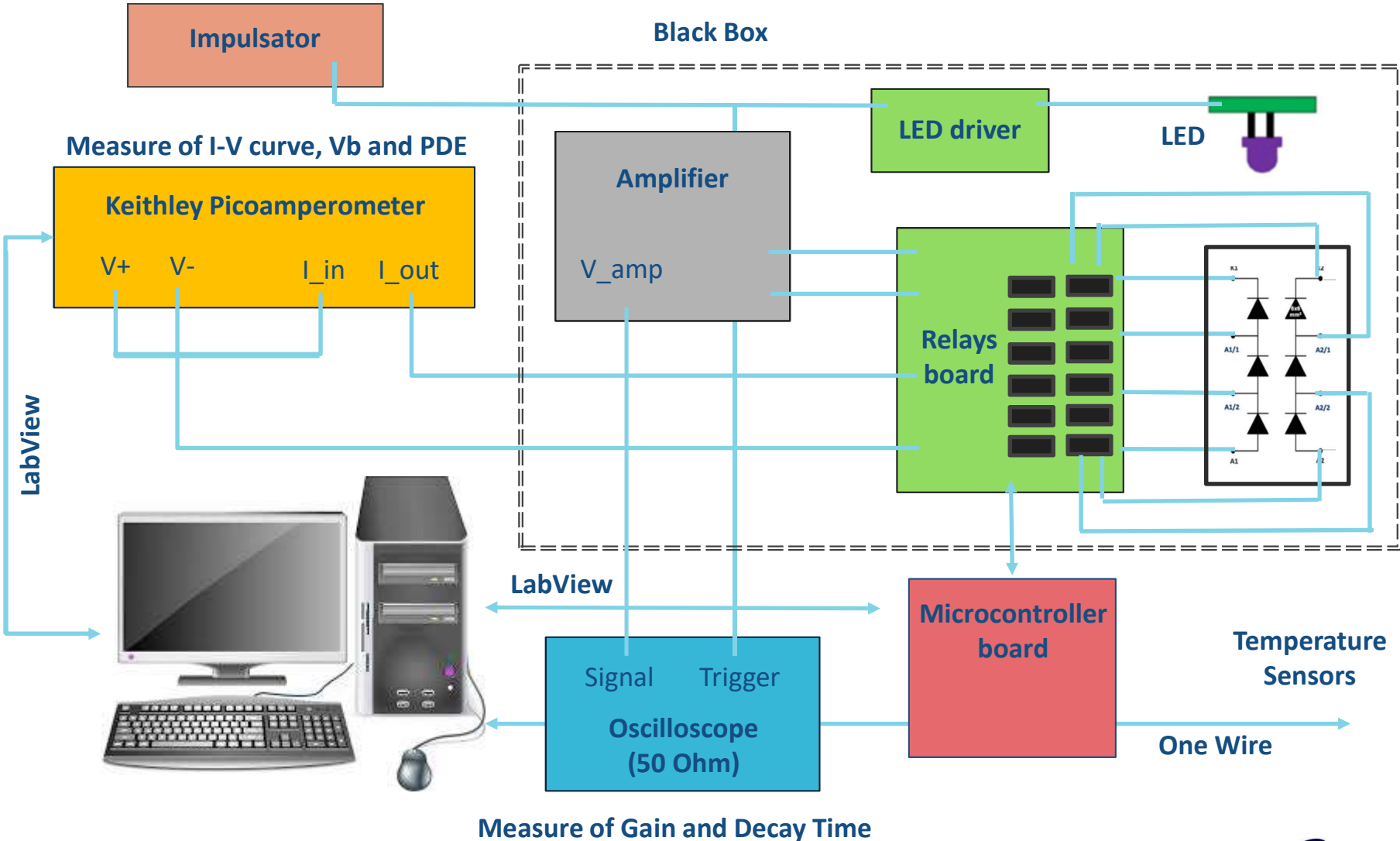
The test involved 105 photosensors from the pre-production, 35 from each of the three vendors: Hamamatsu, SensL and Advansid-FBK.



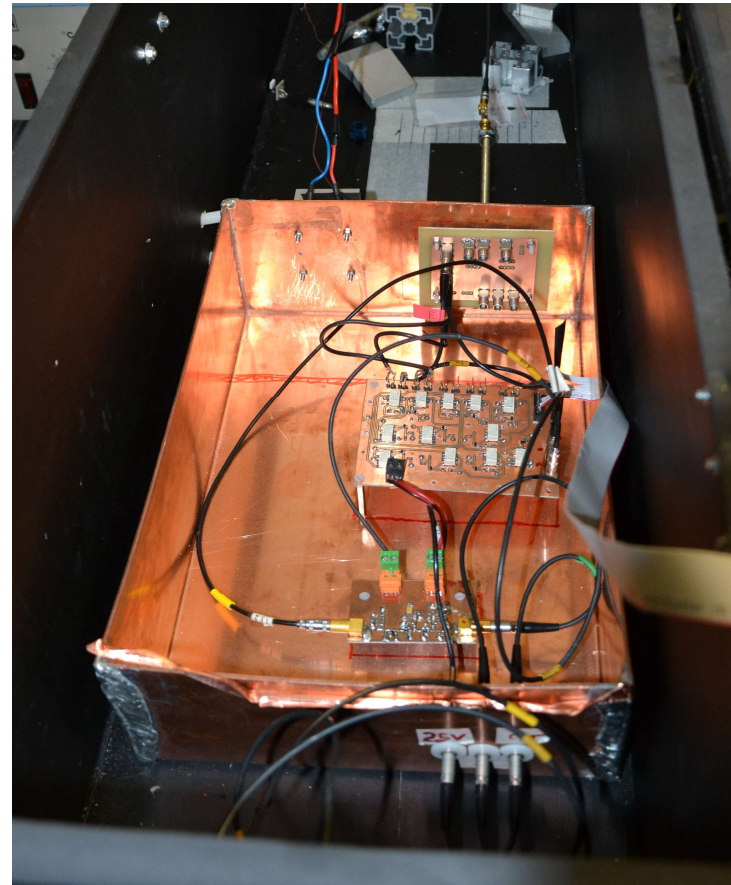
The QA procedure has been performed in a temperature controlled station at 20 that provides for each cell:

- (i) the I-V dark curve from which the breakdown voltage is extracted
- (ii) the Gain at Vop using the photo peaks method
- (iii) the PDE by uniformly flashing the cell with 315 nm few-photons light pulses.

Experimental setup for pre-production QA

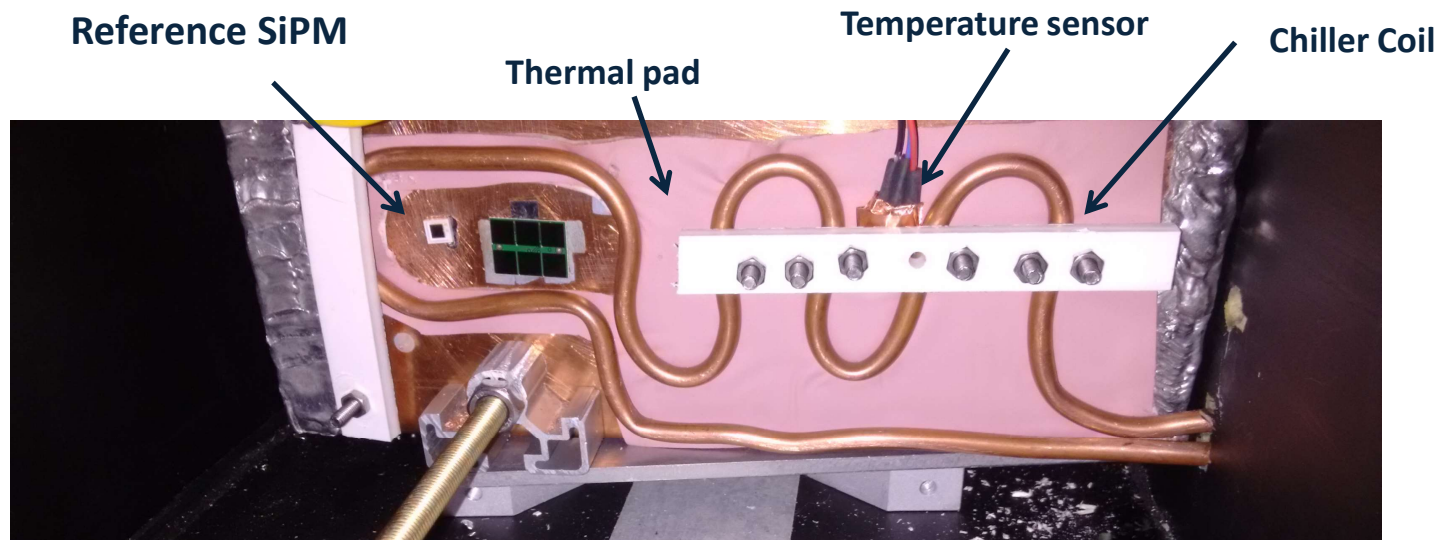


Experimental setup for pre-production QA

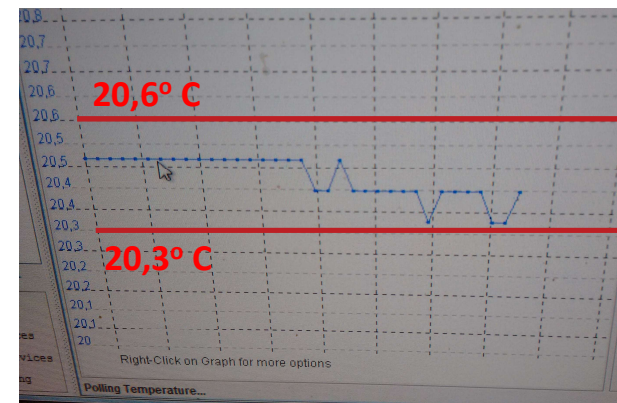


- The relays board and the amplifier are located inside a copper box, which acts as a Faraday cage.
- The UV led emitting at 315 nm is placed at the end of a metal bar bolted to the copper box.

Temperature control

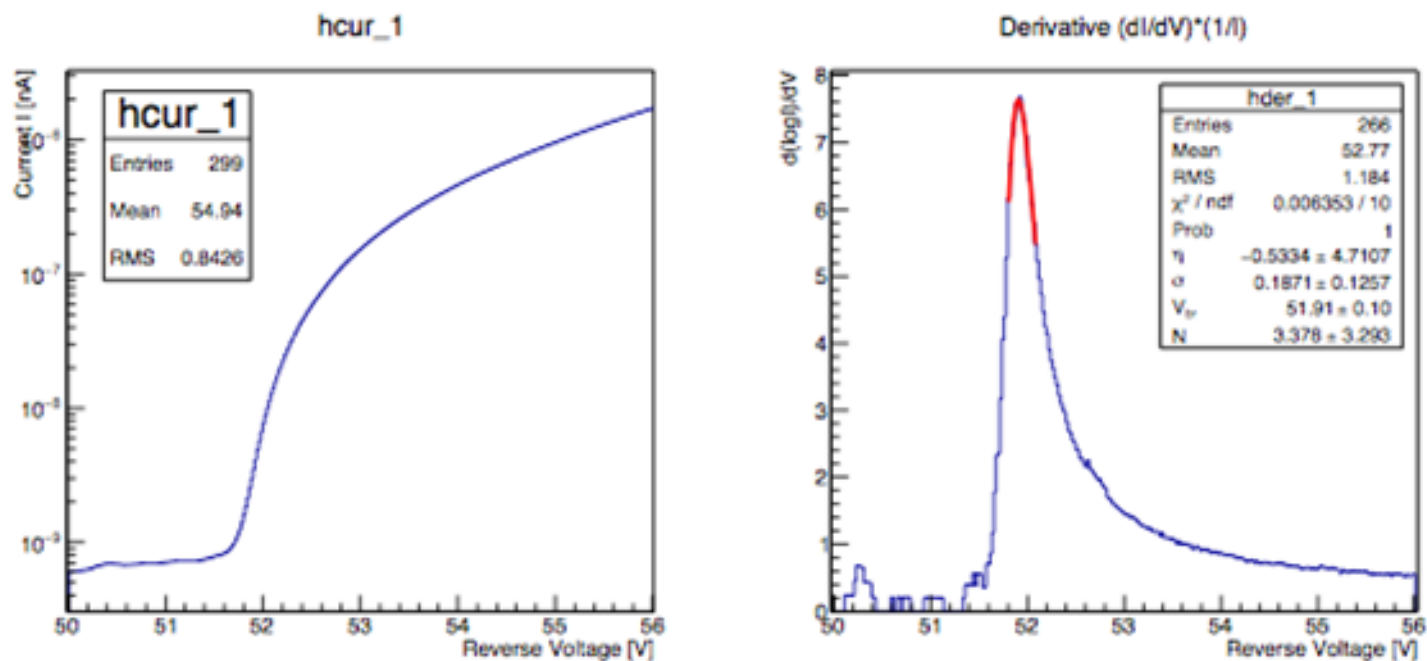


- An external chiller keeps the temperature stable around 20.5°C.
- The temperature is monitored by a one-wire DS18S20 system with an accuracy of 0.3 °C.



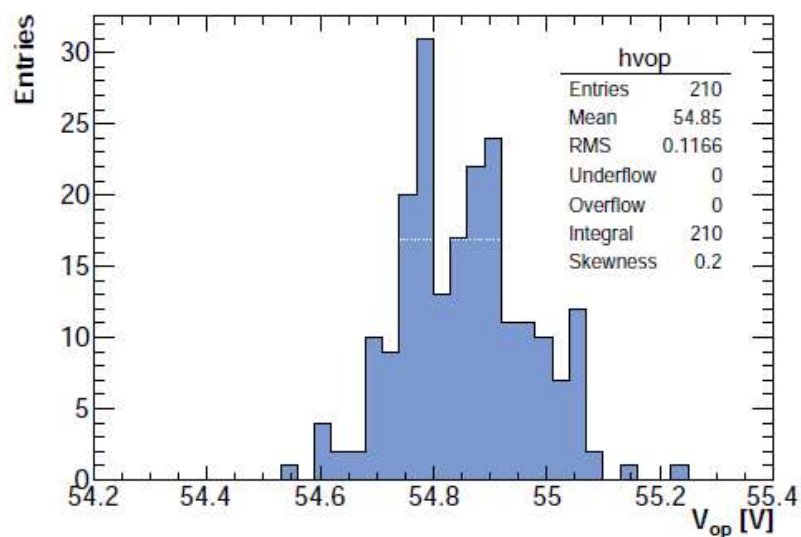
R1: Operative Voltage

- The operative voltage has been defined as $V_{op} = V_b + 3 \text{ V}$.
- We acquired the **I-V dark curve** in a range that varies among the vendors:
 - Hamamatsu [50, 56] V, SensL [24, 30] V, Advansid [26, 32] V
- For each cell we find the peak of **$d(\log(I))/dV - V$** curve to determine the V_b

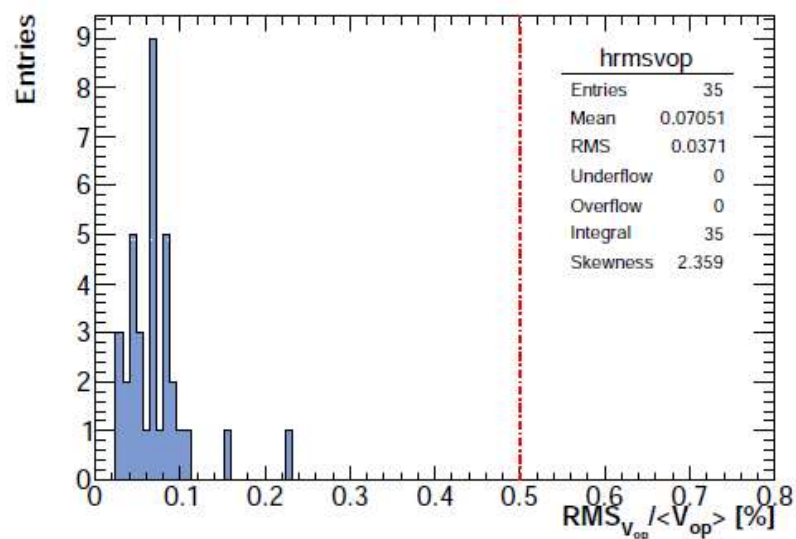


R1: Operative Voltage - Results

Measured Vop



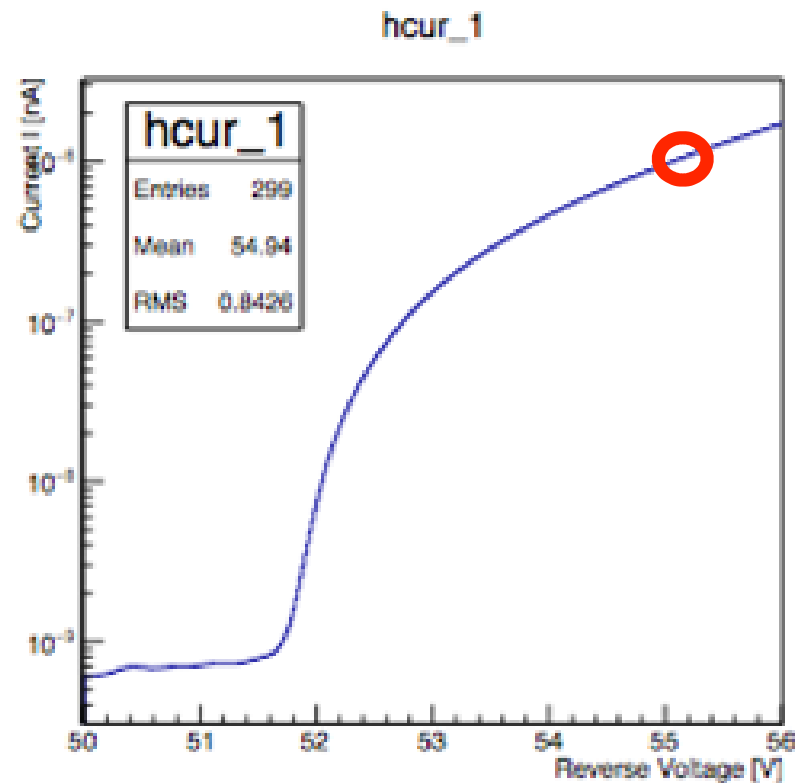
RMS Vop



Example of results from one vendor

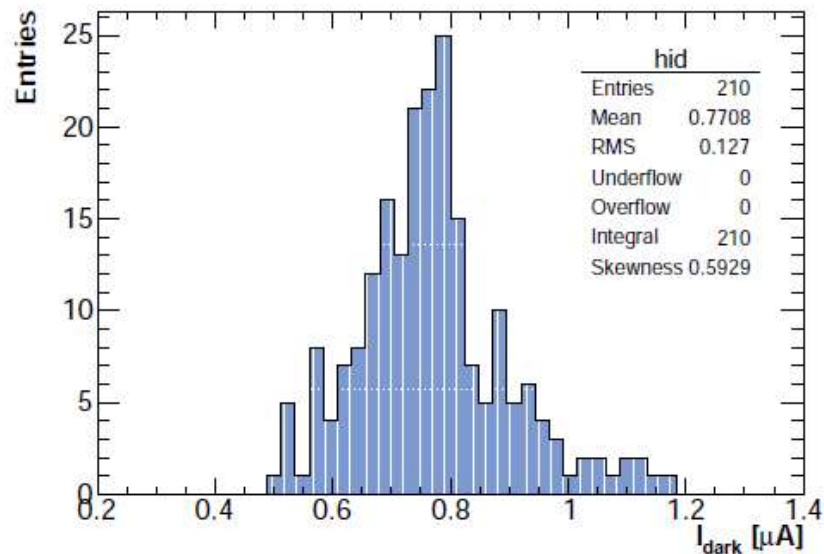
R2: Dark Current at Vop

- From the same I-V scan we obtain also the I_{dark} value at **Vop** for each cell.

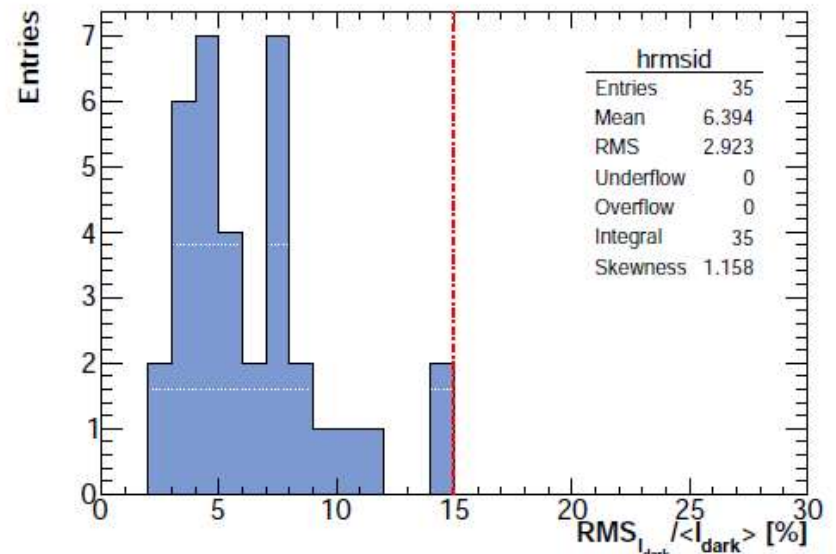


R2: Dark Current at Vop - Results

Measured Id



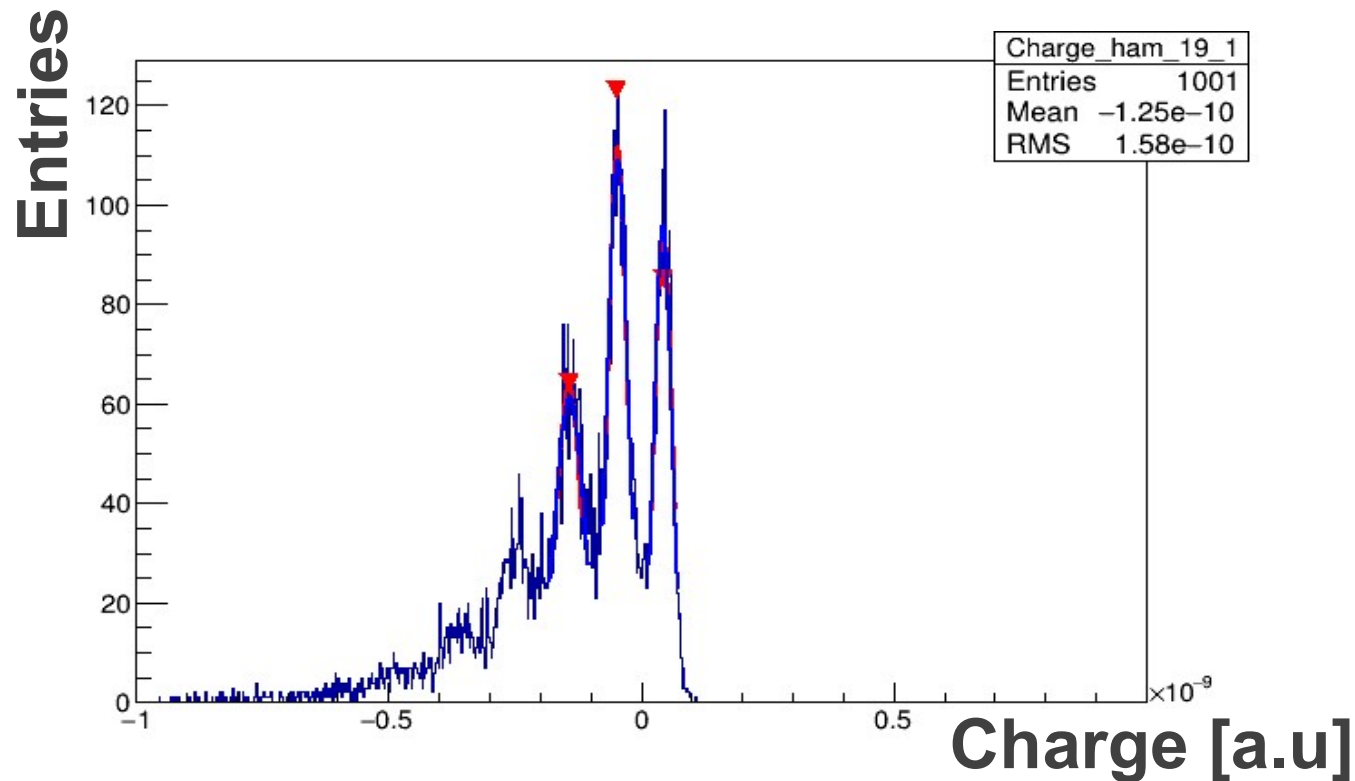
RMS Id



Example of results from one vendor

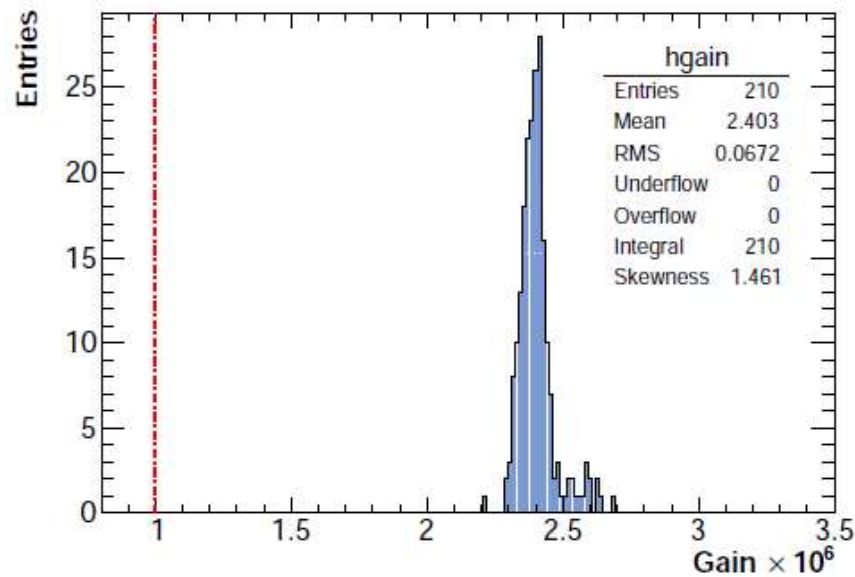
R3 - Gain at Vop

- The LED is powered by 20 ns wide pulses at a frequency of 100 kHz.
- The amplified pulses is integrated in a **gate of 150 ns** (BID requirement).
- Each charge peak corresponds to 0, 1, 2 .. n photons hitting the sensor.
- The gain is therefore obtained from $G = DQ_{\text{peak}}/e \cdot G_{\text{amp}}$.

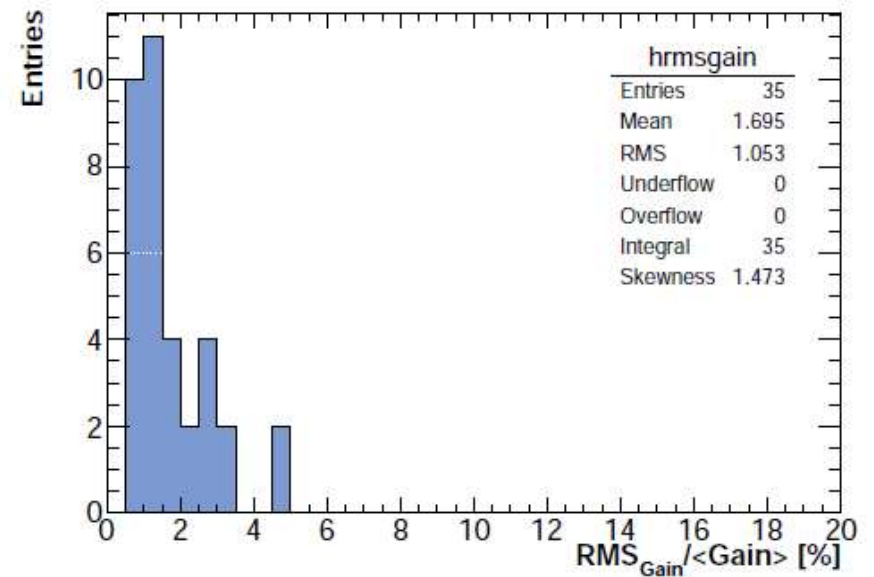


R3 - Gain at Vop - Results

Measured Gain



RMS Gain



Example of results from one vendor

R4 - Relative PDE at Vop [1/3]

- The PDE is defined as n_{pe} , the average number of detected photoelectrons, and N_{γ} , the average number of incident photons on the sensor.
- The probability $P(n)$ of detecting n photons by the sensor is given by the Poisson distribution:

$$P(n, n_{pe}, n_{dark}) = \frac{(n_{pe} + n_{dark})^n \cdot e^{-(n_{pe} + n_{dark})}}{n!}$$

- Inverting the Poisson equation, it is possible to obtain n_{pe} :

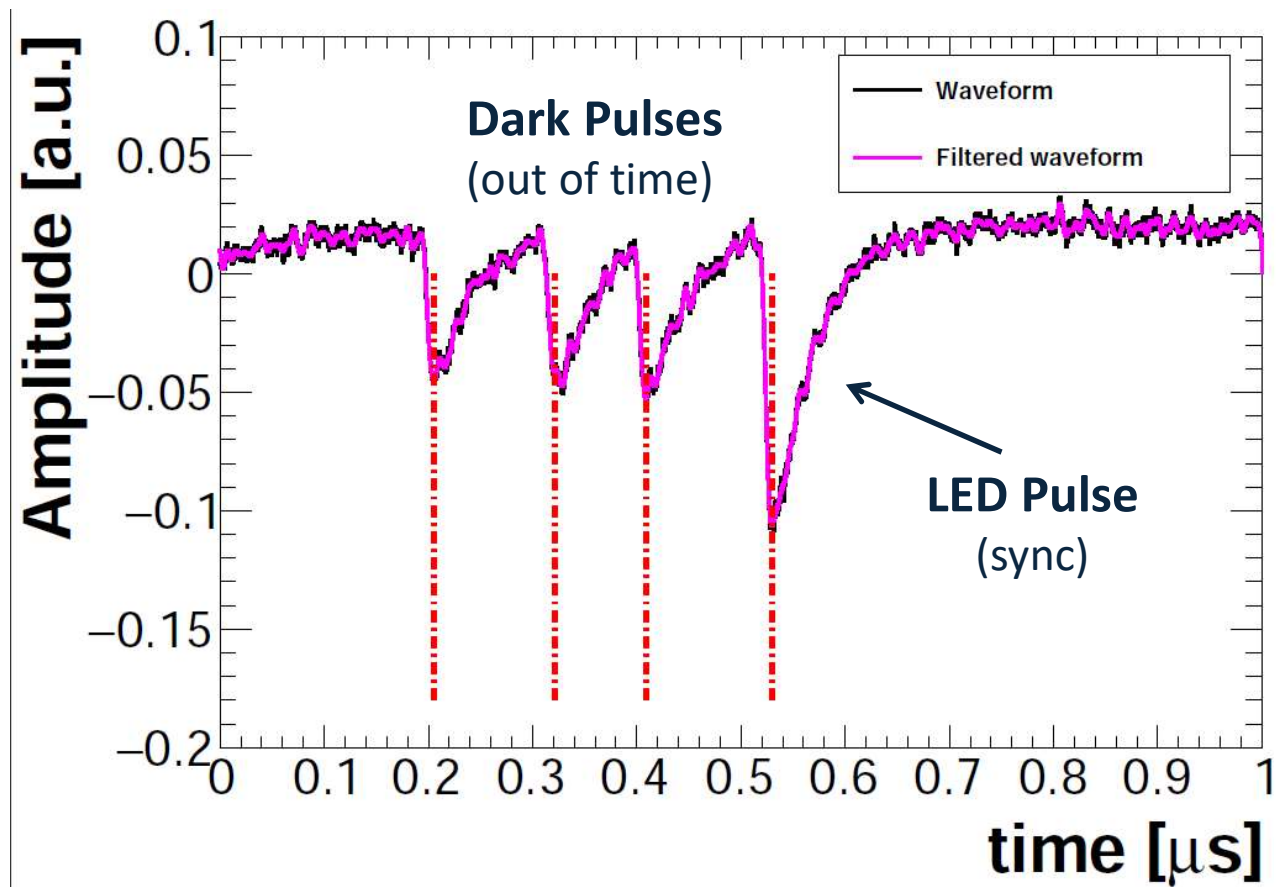
$$n_{pe} = -\ln(P(0, n_{pe}, n_{dark})) + \ln(P(0, n_{dark}))$$

- And express the two probability in quantities measurable by analyzing the signal waveforms, $N_{n>1}$ and N_D :

$$n_{pe} = -\ln\left(1 - \frac{N_{n \geq 1}}{N_T}\right) + \ln\left(1 - \frac{N_D}{N_T}\right)$$

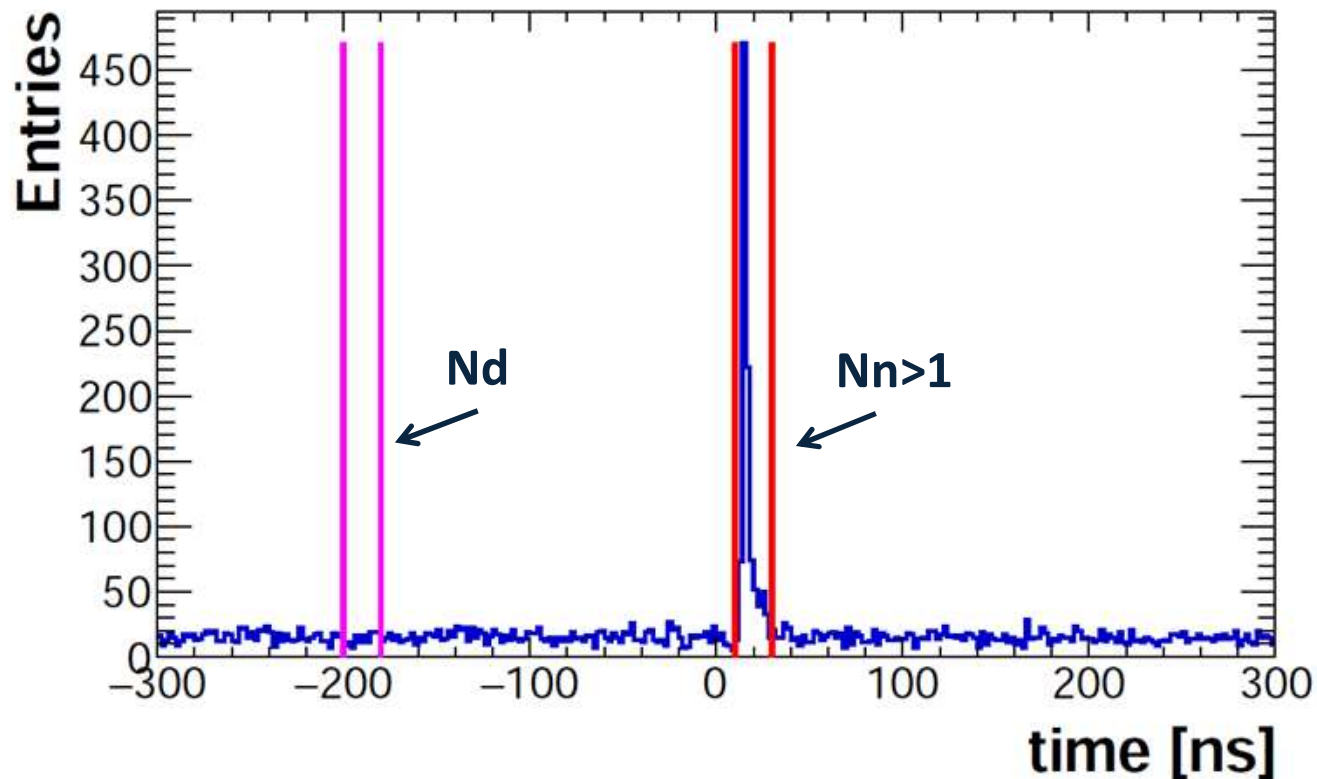
R4 - Relative PDE at Vop [2/3]

- The LED is powered by 20 ns wide pulses at a frequency of 100 kHz.
- Triggering on the light pulse, a waveform of 1 s is acquired.
- The peak time of each pulse is stored.



R4 - Relative PDE at Vop [3/3]

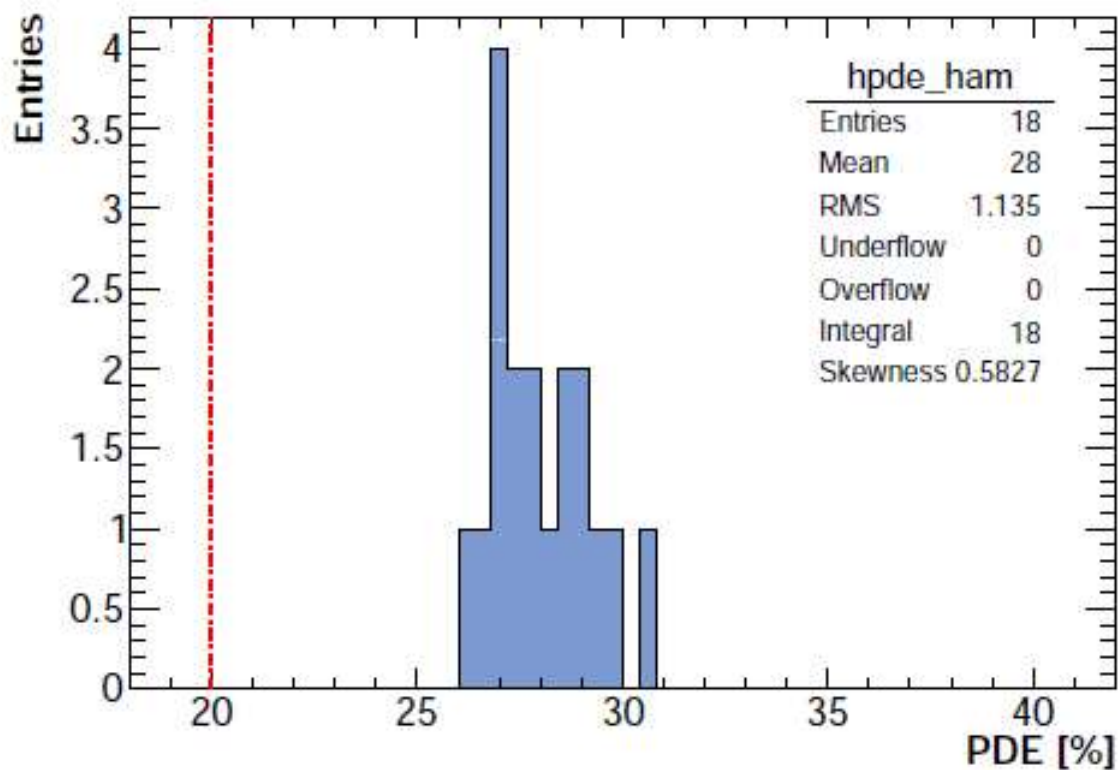
- To evaluate N_{dark} and $N_{n>1}$, we look at the distribution of the peak times, fixing two time gates of 20 ns each.



- To simplify N_{gamma} , the obtained PDE has been rescaled relatively to a reference sensor of well known PDE of 22%.

R4 - Relative PDE at Vop - Results

Measured PDE



Example of results from one vendor

R7 – Recovery Time

- The measurements have been performed in Frascati, using a load of 50 Ohm and after rescaling the time to a 15 Ohm load.

